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Mon, 3 Sep 2007, 4:08:59 PM EST

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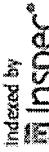
Recent Search Queries

- #1 (resetting flip-flops<and>transition time between normal mode and test mode) **0**

Results

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EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	0	(714/726.ccls.) and ((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:00
L4	0	(714/727.ccls.) and ((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:00
L5	0	(714/730.ccls.) and ((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:00
L6	0	(714/733.ccls.) and ((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:01
L7	0	(714/724.ccls.) and ((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:01
L8	0	(714/42.ccls.) and ((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:01
L9	0	(714/25.ccls.) and ((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:13

EAST Search History

L10	0	((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/03 16:03
L11	0	(327/156.ccls.) and ((integrated adj circuit) with normal with test\$3 with scan\$4) and (reset\$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:13